

**N-Ch MOSFET** 

## **General Description**

The WSG02N20 is the highest performance trench N-Ch MOSFET with extreme high cell density, which provide excellent RDSON and gate charge for most of the small power switching and load switch applications.

The WSG02N20 meet the RoHS and Green Product requirement with full function reliability approved.

#### **Features**

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent Cdv/dt effect decline
- Green Device Available

### **Product Summery**

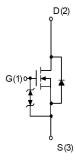
BVDSS	RDSON	ID
200V	310mΩ	2A

## **Applications**

Power Management in TV Inverter.

## **SOT-223 Pin Configuration**





### **Absolute Maximum Ratings**

Symbol	Parameter	Rating	Units	
$V_{DS}$	Drain-Source Voltage	200	V	
$V_{GS}$	Gate-Source Voltage	±20	V	
I <sub>D</sub> @T <sub>c</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	2.0	Α	
I <sub>D</sub> @T <sub>c</sub> =70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	1.5	Α	
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	10	Α	
P <sub>D</sub> @T <sub>A</sub> =25℃	Total Power Dissipation <sup>3</sup>	18	W	
T <sub>STG</sub>	Storage Temperature Range -55 to 150		$^{\circ}$	
$T_J$	Operating Junction Temperature Range -55 to		${\mathbb C}$	

#### **Thermal Data**

Symbol	Parameter	Тур.	Max.	Unit
$R_{ heta JA}$	Thermal Resistance Junction-ambient <sup>1</sup>		70	°C/W
$R_{ heta JC}$	Thermal Resistance Junction-Case <sup>1</sup>		30	°C/W

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# Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ =0V , $I_D$ =250uA	200			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25℃ , I <sub>D</sub> =1mA		0.098		V/°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =2A		310	410	mΩ
		V <sub>GS</sub> =6V , I <sub>D</sub> =1A		314	820	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	\/ -\/   -250uA	2.0	2.8	4.0	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA		-4.57		mV/℃
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{DS}$ =80V , $V_{GS}$ =0V , $T_J$ =25 $^{\circ}$ C			1	
		$V_{DS}$ =80V , $V_{GS}$ =0V , $T_J$ =55 $^{\circ}$ C			5	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ = $\pm 20 V$ , $V_{DS}$ = $0 V$			±100	nA
gfs	Forward Transconductance	$V_{DS}$ =5 $V$ , $I_{D}$ =2 $A$		15		S
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		2.5		Ω
$Q_g$	Total Gate Charge (10V)	V <sub>DS</sub> =30V , V <sub>GS</sub> =10V , I <sub>D</sub> =2A		51.7		
$Q_gs$	Gate-Source Charge			12.7		nC
Q <sub>gd</sub>	Gate-Drain Charge			16.3		
T <sub>d(on)</sub>	Turn-On Delay Time			32	50	
Tr	Rise Time	V <sub>DD</sub> =30V , V <sub>GEN</sub> =10V ,		32.1	51	- ns
T <sub>d(off)</sub>	Turn-Off Delay Time	$R_G$ =4.7 $\Omega$ $I_D$ =1A , $R_L$ =17.7 $\Omega$		60.9	79	
T <sub>f</sub>	Fall Time			5.2	10	
Ciss	Input Capacitance	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , f=1MHz		645		
C <sub>oss</sub>	Output Capacitance			68		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			21		

### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,4</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			2	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,4</sup>				10	Α
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25℃			1.15	V
t <sub>rr</sub>	Reverse Recovery Time	lF=2A,dl/dt=100A/μs , T <sub>J</sub> =25℃		38		nS
$Q_{rr}$	Reverse Recovery Charge			56		nC

#### Note:

<sup>1.</sup> The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, t≦10sec.

<sup>2.</sup>The data tested by pulsed , pulse width  $\leq 300 \text{us}$  , duty cycle  $\leq 2\%$ 

<sup>3.</sup>The power dissipation is limited by 150  $^{\circ}\mathrm{C}$  junction temperature

<sup>4.</sup> The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.

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# **Typical Characteristics**

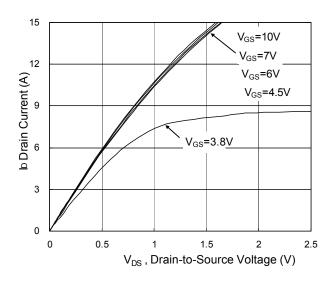


Fig.1 Typical Output Characteristics

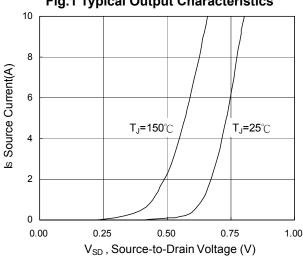


Fig.3 Forward Characteristics Of Reverse

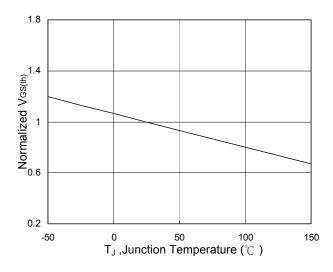


Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$ 

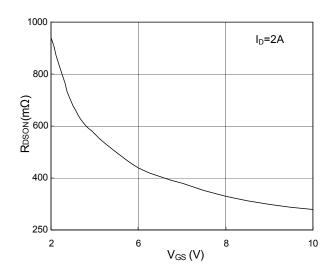


Fig.2 On-Resistance vs. Gate-Source

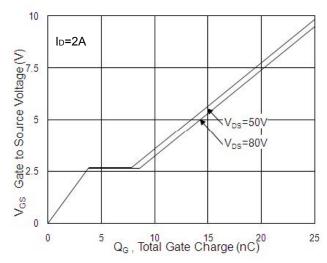


Fig.4 Gate-Charge Characteristics

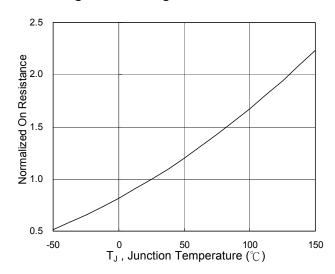
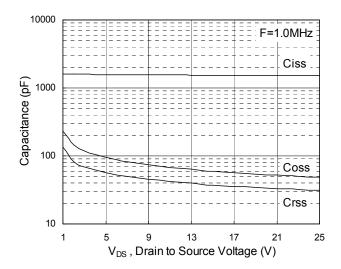


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>





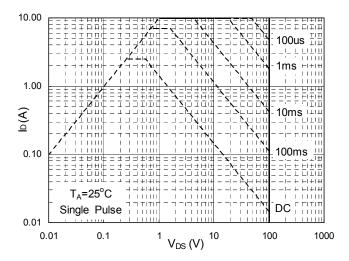


Fig.7 Capacitance

Fig.8 Safe Operating Area

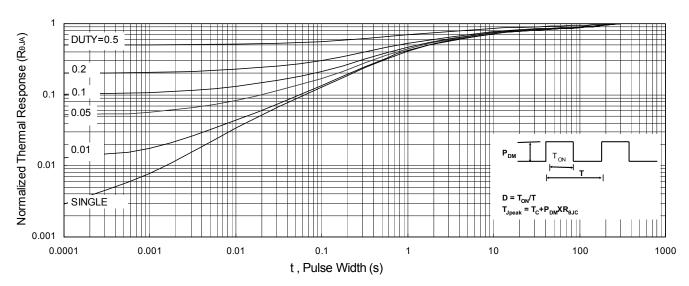
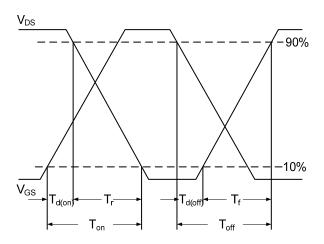
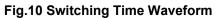


Fig.9 Normalized Maximum Transient Thermal Impedance





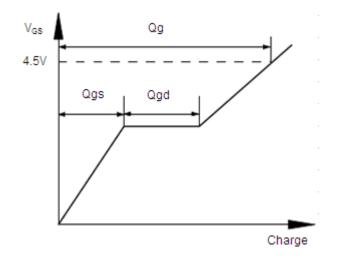


Fig.11 Gate Charge Waveform



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